

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 283425US0PCT		SERIAL NO. 10/562,121	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Carole BAUBET, et al.					
		FILING DATE June 28, 2006		GROUP 1794			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AD						
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	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	Influence of Ar ion-beam assistance and annealing temperatures on properties of TiO ₂ thin films deposited by reactive DC magnetron sputtering, Sung-Hwa Kim, et al., Elsevier, pp. 155-159, Thin Solid Films 475 (2005).						
AX	DC reactive magnetron sputtering with Ar ion-beam assistance for titanium oxide films, S.-H. Kim, et al., Elsevier, pp. 457-464, Surface and Coatings Technology 158-159 (2002).						
AY	The effect of the ion beam energy on the properties of indium tin oxide thin films prepared by ion beam assisted deposition, Li-Jian Meng, et al., Elsevier, pp. 1365-1369, Thin Solid Films 516 (2008).						
AZ	Structure and properties of TiO ₂ films prepared by ion beam assisted deposition, Xiaoling Cheng, et al., Elsevier, pp. 5552-5555, Surface Coatings & Technology 201 (2007).			<input type="checkbox"/> Additional References sheet(s) attached			
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							